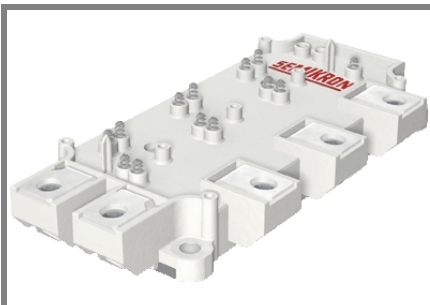


# SEMiX 151GD066HDs



**SEMiX® 13s**

## Trench IGBT Modules

### SEMiX 151GD066HDs

Preliminary Data

#### Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient

#### Typical Applications

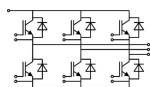
- Matrix Converter
- Resonant Inverter
- Current Source Inverter

#### Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_j=150^\circ\text{C}$
- use of soft RG necessary
- take care of over-voltage caused by stray inductance

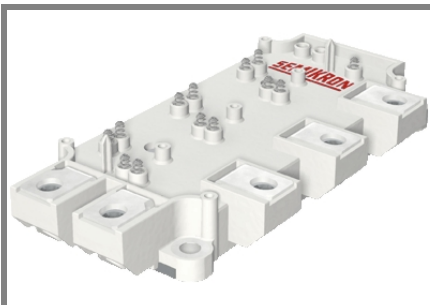
Absolute Maximum Ratings		$T_{case} = 25^\circ\text{C}$ , unless otherwise specified		
Symbol	Conditions	Values	Units	
<b>IGBT</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	600	V	
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	200	A
		$T_c = 80^\circ\text{C}$	150	A
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$	300	A	
$V_{GES}$		$\pm 20$	V	
$t_{psc}$	$V_{CC} = 360\text{ V}; V_{GE} \leq 15\text{ V}; T_j = 150^\circ\text{C}$ $V_{CES} < 600\text{ V}$	6	$\mu\text{s}$	
<b>Inverse Diode</b>				
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	220	A
		$T_c = 80^\circ\text{C}$	160	A
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	300	A	
$I_{FSM}$	$t_p = 10\text{ ms}; \text{sin.}$	$T_j = 25^\circ\text{C}$	980	A
<b>Module</b>				
$I_{t(RMS)}$		600	A	
$T_{vj}$		- 40 ... + 175 (125)	$^\circ\text{C}$	
$T_{stg}$		- 40 ... + 125	$^\circ\text{C}$	
$V_{isol}$	AC, 1 min.	4000	V	

Characteristics		$T_{case} = 25^\circ\text{C}$ , unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
<b>IGBT</b>					
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 2,4\text{ mA}$		5,8		V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$			0,45	mA
$V_{CE0}$		$T_j = 25^\circ\text{C}$	0,9	1	V
		$T_j = 150^\circ\text{C}$	0,85	0,9	V
$r_{CE}$	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	3,7	6	m $\Omega$
		$T_j = 150^\circ\text{C}$	5,7	8	m $\Omega$
$V_{CE(sat)}$	$I_{Cnom} = 150\text{ A}, V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}_{chiplev.}$	1,45	1,9	V
		$T_j = 150^\circ\text{C}_{chiplev.}$	1,7	2,1	V
$C_{ies}$	$V_{CE} = 25, V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	9,2		nF
$C_{oes}$			0,6		nF
$C_{res}$			0,28		nF
$Q_G$	$V_{GE} = -8 \dots +15\text{V}$		1200		nC
$t_{d(on)}$	$R_{Gon} = 4,5\ \Omega$	$V_{CC} = 300\text{V}$ $I_{Cnom} = 150\text{A}$	140		ns
$t_r$			40		ns
$E_{on}$	$R_{Goff} = 4,5\ \Omega$	$T_j = 150^\circ\text{C}$	3,8		mJ
$t_{d(off)}$			385		ns
$t_f$			40		ns
$E_{off}$			6,1		mJ
$R_{th(j-c)}$	per IGBT		0,29		K/W



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# SEMiX 151GD066HDs



**SEMiX® 13s**

## Trench IGBT Modules

### SEMiX 151GD066HDs

#### Preliminary Data

#### Features

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- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient

#### Typical Applications

- Matrix Converter
- Resonant Inverter
- Current Source Inverter

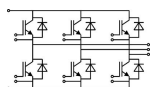
#### Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_j=150^\circ\text{C}$
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- take care of over-voltage caused by stray inductance

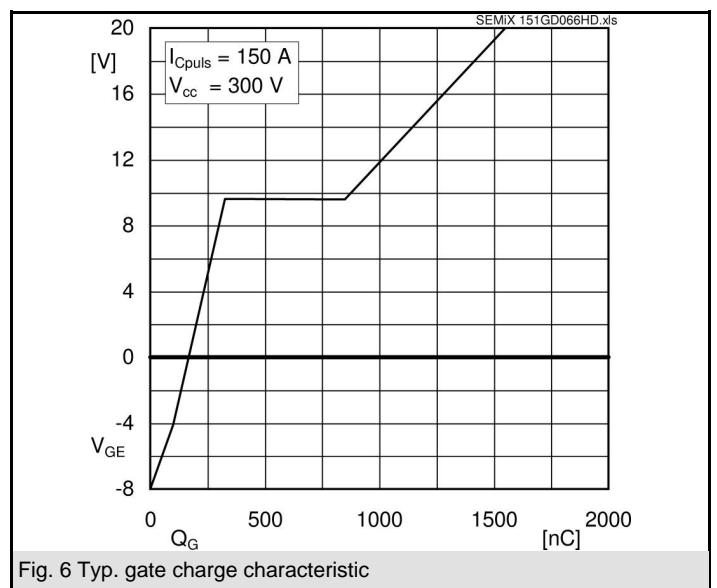
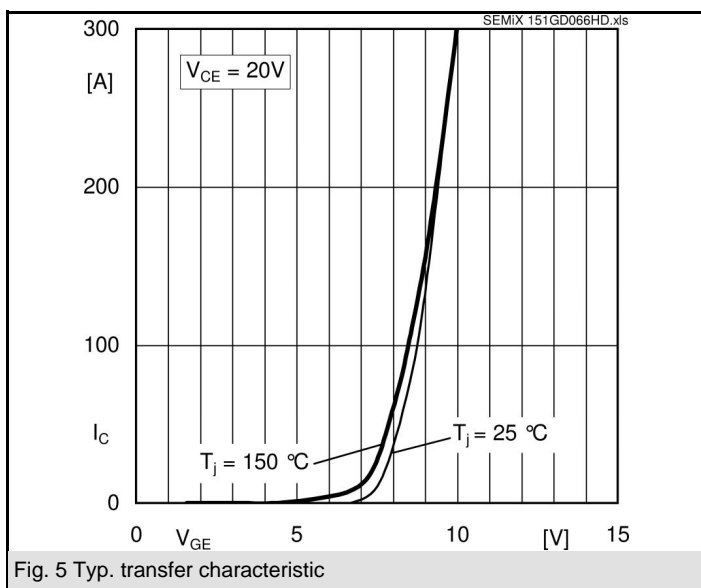
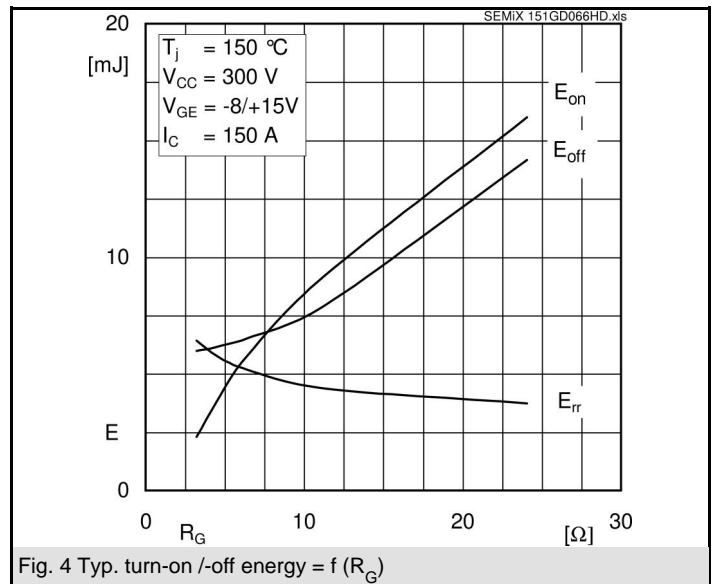
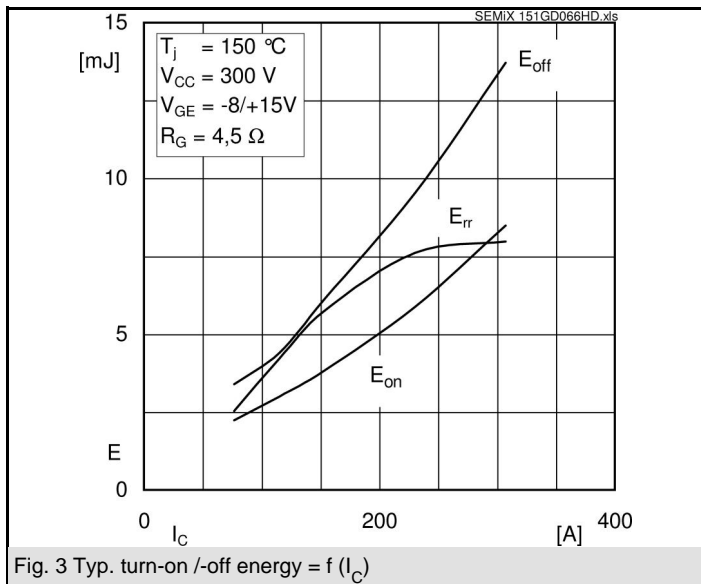
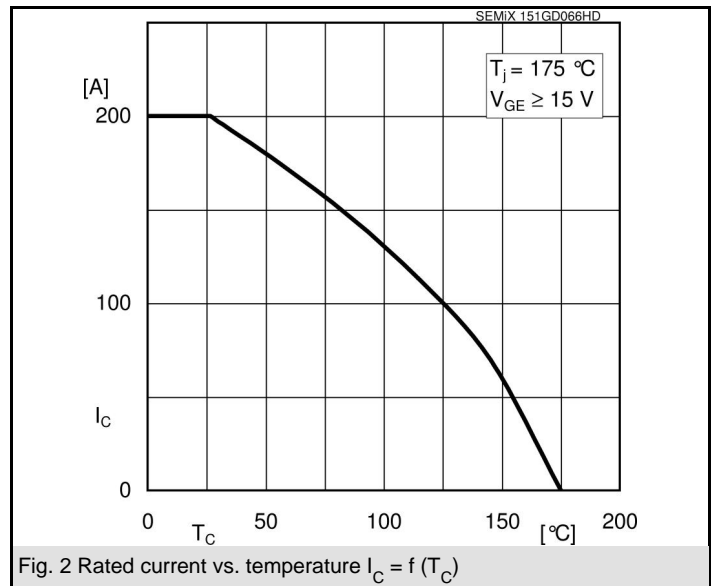
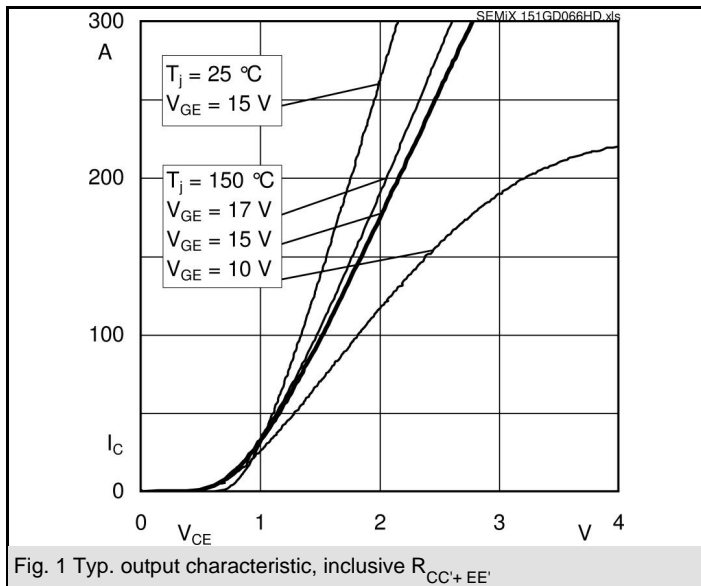
Characteristics		min.	typ.	max.	Units
<b>Inverse Diode</b>					
$V_F = V_{EC}$	$I_{Fnom} = 150 \text{ A}; V_{GE} = 0 \text{ V}$		1,4	1,6	V
	$T_j = 25^\circ\text{C}_{chiplev.}$				
	$T_j = 150^\circ\text{C}_{chiplev.}$		1,4	1,6	V
$V_{F0}$			1	1,1	V
	$T_j = 25^\circ\text{C}$				
	$T_j = 150^\circ\text{C}$		0,85	0,95	V
$r_F$			2,7	3,5	mΩ
	$T_j = 25^\circ\text{C}$				
	$T_j = 150^\circ\text{C}$		3,7	4,5	mΩ
$I_{RRM}$	$I_{Fnom} = 150 \text{ A}$		155		A
$Q_{rr}$	$di/dt = 3000 \text{ A}/\mu\text{s}$		24		μC
$E_{rr}$	$V_{GE} = -8 \text{ V}; V_{CC} = 300 \text{ V}$		5,8		mJ
$R_{th(j-c)D}$	per diode			0,36	K/W
<b>Module</b>					
$L_{CE}$			20		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_{case} = 25^\circ\text{C}$	0,7		mΩ
		$T_{case} = 125^\circ\text{C}$	1		mΩ
$R_{th(c-s)}$	per module		0,04		K/W
$M_s$	to heat sink (M5)		3	5	Nm
$M_t$	to terminals (M6)		2,5	5	Nm
w				350	g
<b>Temperature sensor</b>					
$R_{100}$	$T_c = 100^\circ\text{C}$ ( $R_{25} = 5 \text{ k}\Omega$ )		0,493±5%		kΩ
$B_{100/125}$	$R(T) = R_{100} \exp[B_{100/125} (1/T - 1/T_{100})]$ $T[\text{K}]; B$		3550±2%		K

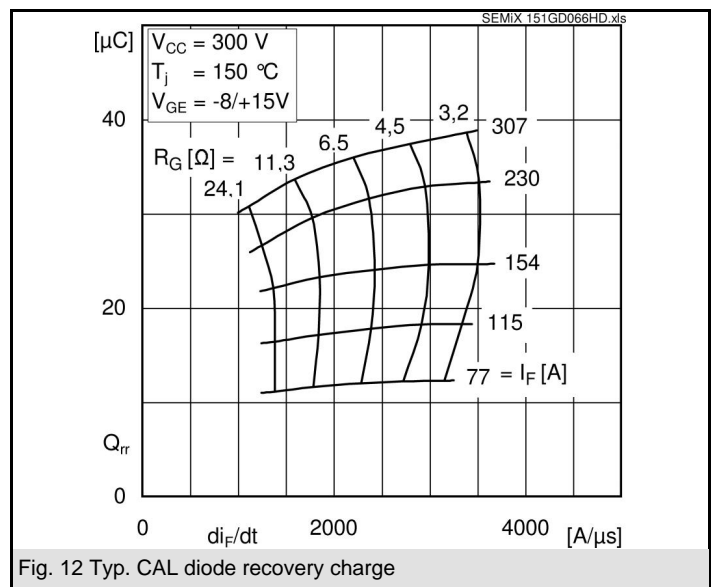
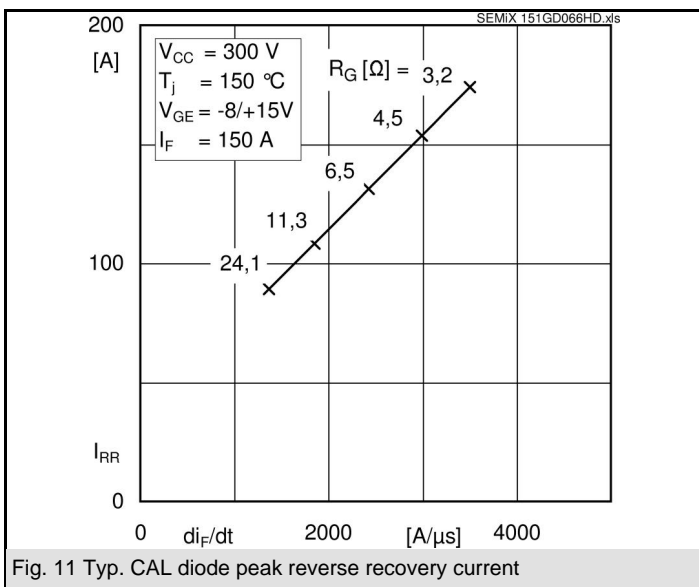
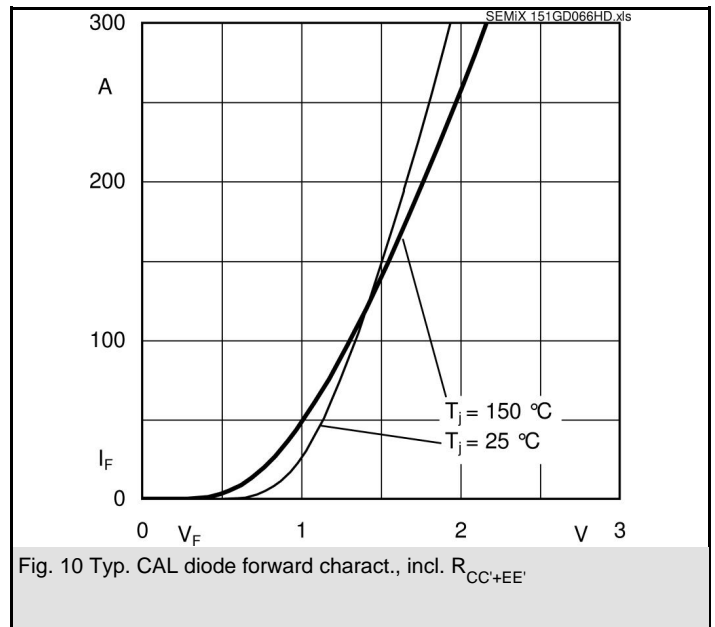
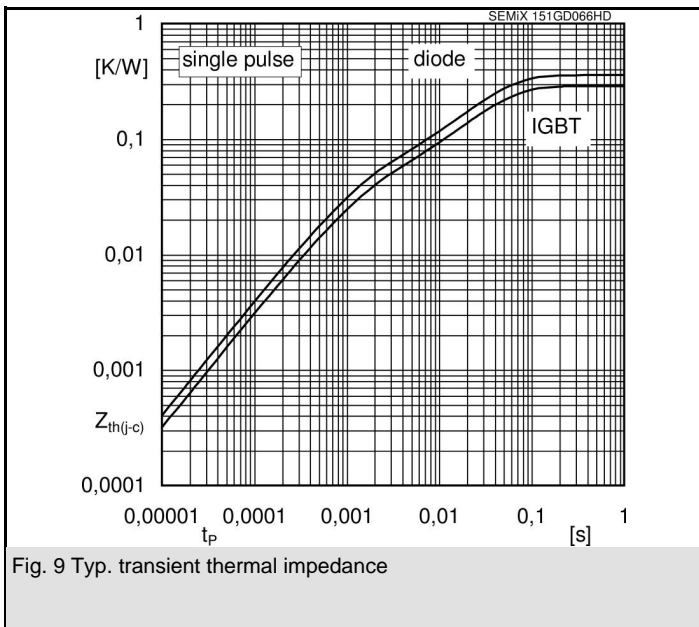
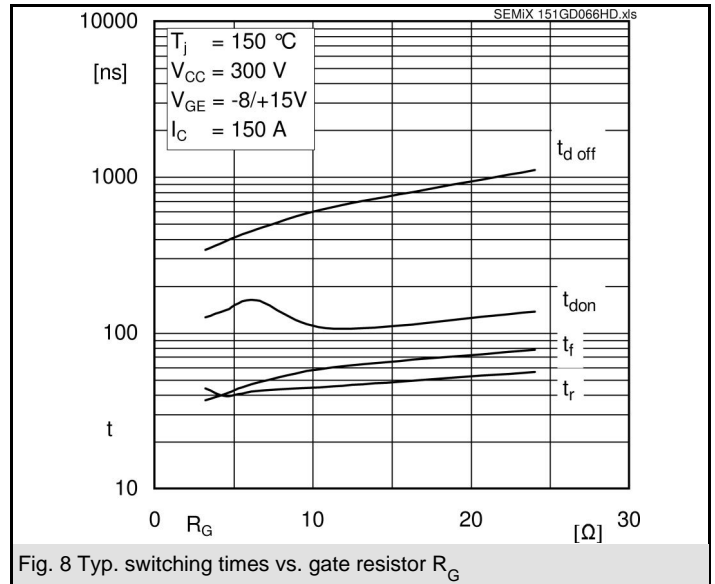
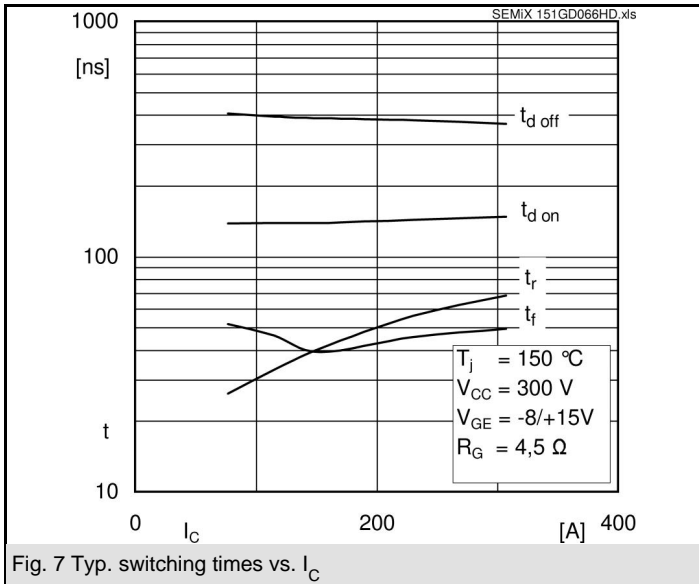
This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.



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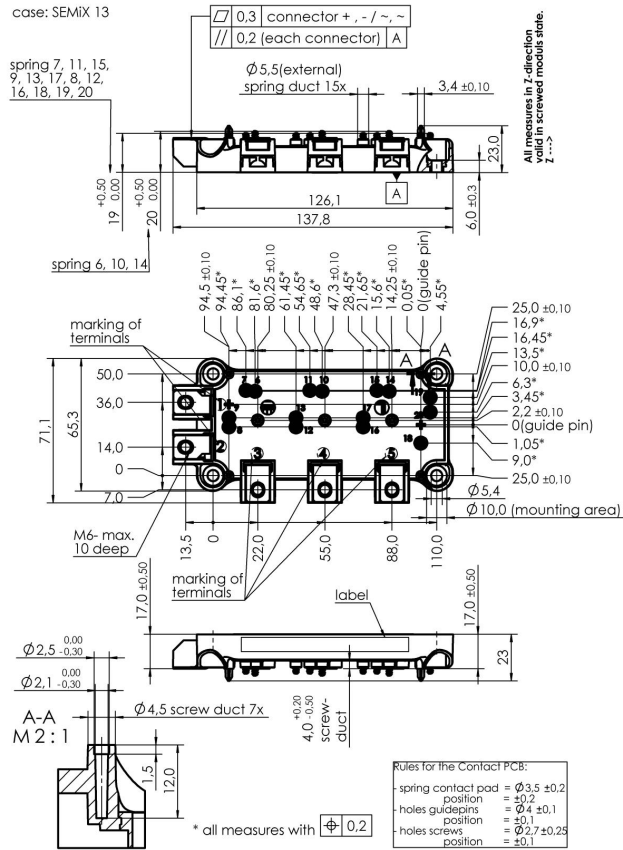




# SEMiX 151GD066HDs

UL Recognized  
File no. E 63 532

Dimensions in mm



Case SEMiX 13s

